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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.2GHz
Co-Processors/DSP	Signal Processing; SPE
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	1023-BFBGA, FCBGA
Supplier Device Package	1023-FCBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8572vtatle

- Supports fully nested interrupt delivery
- Interrupts can be routed to external pin for external processing.
- Interrupts can be routed to the e500 core's standard or critical interrupt inputs.
- Interrupt summary registers allow fast identification of interrupt source.
- Integrated security engine (SEC) optimized to process all the algorithms associated with IPsec, IKE, SSL/TLS, SRTP, 802.16e, and 3GPP
 - Four crypto-channels, each supporting multi-command descriptor chains
 - Dynamic assignment of crypto-execution units through an integrated controller
 - Buffer size of 256 bytes for each execution unit, with flow control for large data sizes
 - PKEU—public key execution unit
 - RSA and Diffie-Hellman; programmable field size up to 4096 bits
 - Elliptic curve cryptography with F_{2^m} and $F(p)$ modes and programmable field size up to 1023 bits
 - DEU—Data Encryption Standard execution unit
 - DES, 3DES
 - Two key (K1, K2, K1) or three key (K1, K2, K3)
 - ECB, CBC and OFB-64 modes for both DES and 3DES
 - AESU—Advanced Encryption Standard unit
 - Implements the Rijndael symmetric key cipher
 - ECB, CBC, CTR, CCM, GCM, CMAC, OFB-128, CFB-128, and LRW modes
 - 128-, 192-, and 256-bit key lengths
 - AFEU—ARC four execution unit
 - Implements a stream cipher compatible with the RC4 algorithm
 - 40- to 128-bit programmable key
 - MDEU—message digest execution unit
 - SHA-1 with 160-bit message digest
 - SHA-2 (SHA-256, SHA-384, SHA-512)
 - MD5 with 128-bit message digest
 - HMAC with all algorithms
 - KEU—Kasumi execution unit
 - Implements F8 algorithm for encryption and F9 algorithm for integrity checking
 - Also supports A5/3 and GEA-3 algorithms
 - RNG—random number generator
 - XOR engine for parity checking in RAID storage applications
 - CRC execution unit
 - CRC-32 and CRC-32C
- Pattern Matching Engine with DEFLATE decompression

Figure 4 shows the DDR2 and DDR3 SDRAM Interface output timing for the MCK to MDQS skew measurement (t_{DDKHMH}).

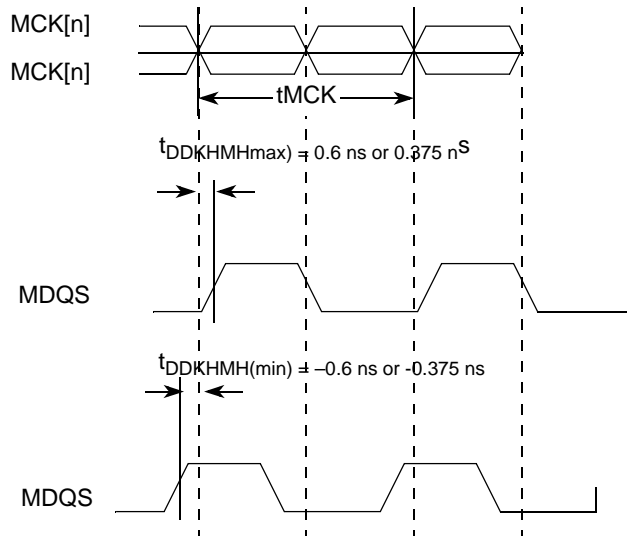


Figure 4. Timing Diagram for t_{DDKHMH}

Figure 5 shows the DDR2 and DDR3 SDRAM Interface output timing diagram.

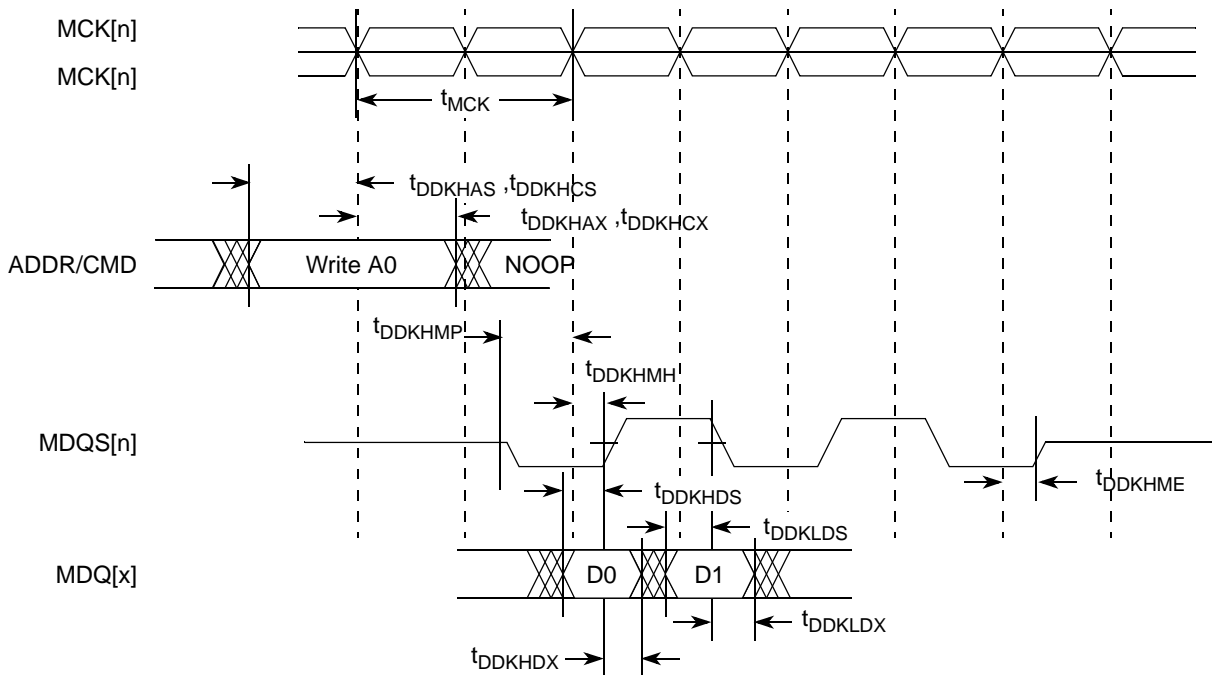


Figure 5. DDR2 and DDR3 SDRAM Interface Output Timing Diagram

Figure 17 shows the TBI receive the timing diagram.

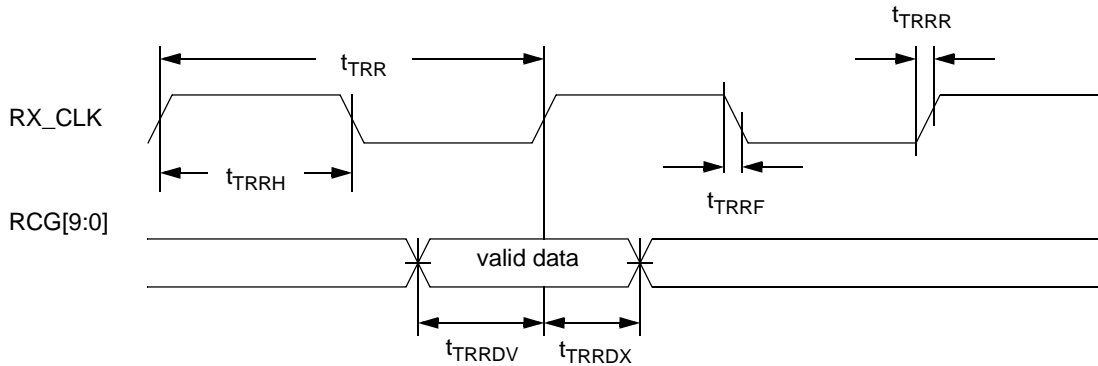


Figure 17. TBI Single-Clock Mode Receive AC Timing Diagram

8.2.6 RGMII and RTBI AC Timing Specifications

Table 34 presents the RGMII and RTBI AC timing specifications.

Table 34. RGMII and RTBI AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of $2.5\text{ V} \pm 5\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
Data to clock output skew (at transmitter)	t_{SKRGT}	-500	0	500	ps
Data to clock input skew (at receiver) ²	t_{SKRGT}	1.0	—	2.8	ns
Clock period ³	t_{RGT}	7.2	8.0	8.8	ns
Duty cycle for 10BASE-T and 100BASE-TX ^{3, 4}	t_{RGTH}/t_{RGT}	40	50	60	%
Rise time (20%–80%)	t_{RGTR}	—	—	0.75	ns
Fall time (20%–80%)	t_{RGTF}	—	—	0.75	ns

Notes:

- Note that, in general, the clock reference symbol representation for this section is based on the symbols RGT to represent RGMII and RTBI timing. For example, the subscript of t_{RGT} represents the TBI (T) receive (RX) clock. Note also that the notation for rise (R) and fall (F) times follows the clock symbol that is being represented. For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (RGT).
- This implies that PC board design requires clocks to be routed such that an additional trace delay of greater than 1.5 ns will be added to the associated clock signal.
- For 10 and 100 Mbps, t_{RGT} scales to $400\text{ ns} \pm 40\text{ ns}$ and $40\text{ ns} \pm 4\text{ ns}$, respectively.
- Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet's clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three t_{RGT} of the lowest speed transitioned between.

8.3.4 SGMII AC Timing Specifications

This section describes the SGMII transmit and receive AC timing specifications. Transmitter and receiver characteristics are measured at the transmitter outputs ($\overline{SD2_TX[n]}$ and $\overline{SD2_TX}[n]$) or at the receiver inputs ($\overline{SD2_RX}[n]$ and $\overline{SD2_RX}[n]$) as depicted in [Figure 25](#), respectively.

8.3.4.1 SGMII Transmit AC Timing Specifications

[Table 40](#) provides the SGMII transmit AC timing targets. A source synchronous clock is not provided.

Table 40. SGMII Transmit AC Timing Specifications

At recommended operating conditions with $XV_{DD_SRDS2} = 1.1V \pm 5\%$.

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Deterministic Jitter	JD	—	—	0.17	UI p-p	—
Total Jitter	JT	—	—	0.35	UI p-p	—
Unit Interval	UI	799.92	800	800.08	ps	1
V_{OD} fall time (80%-20%)	t _{fall}	50	—	120	ps	—
V_{OD} rise time (20%-80%)	t _{rise}	50	—	120	ps	—

Notes:

- Each UI is 800 ps \pm 100 ppm.

8.3.4.2 SGMII Receive AC Timing Specifications

[Table 41](#) provides the SGMII receive AC timing specifications. Source synchronous clocking is not supported. Clock is recovered from the data. [Figure 24](#) shows the SGMII receiver input compliance mask eye diagram.

Table 41. SGMII Receive AC Timing Specifications

At recommended operating conditions with $XV_{DD_SRDS2} = 1.1V \pm 5\%$.

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Deterministic Jitter Tolerance	JD	0.37	—	—	UI p-p	1
Combined Deterministic and Random Jitter Tolerance	JDR	0.55	—	—	UI p-p	1
Sinusoidal Jitter Tolerance	JSIN	0.1	—	—	UI p-p	1
Total Jitter Tolerance	JT	0.65	—	—	UI p-p	1
Bit Error Ratio	BER	—	—	10^{-12}	—	—
Unit Interval	UI	799.92	800	800.08	ps	2
AC Coupling Capacitor	C _{TX}	5	—	200	nF	3

Notes:

- Measured at receiver.
- Each UI is 800 ps \pm 100 ppm.
- The external AC coupling capacitor is required. It is recommended to be placed near the device transmitter outputs.
- See *RapidIO 1x/4x LP Serial Physical Layer Specification* for interpretation of jitter specifications.

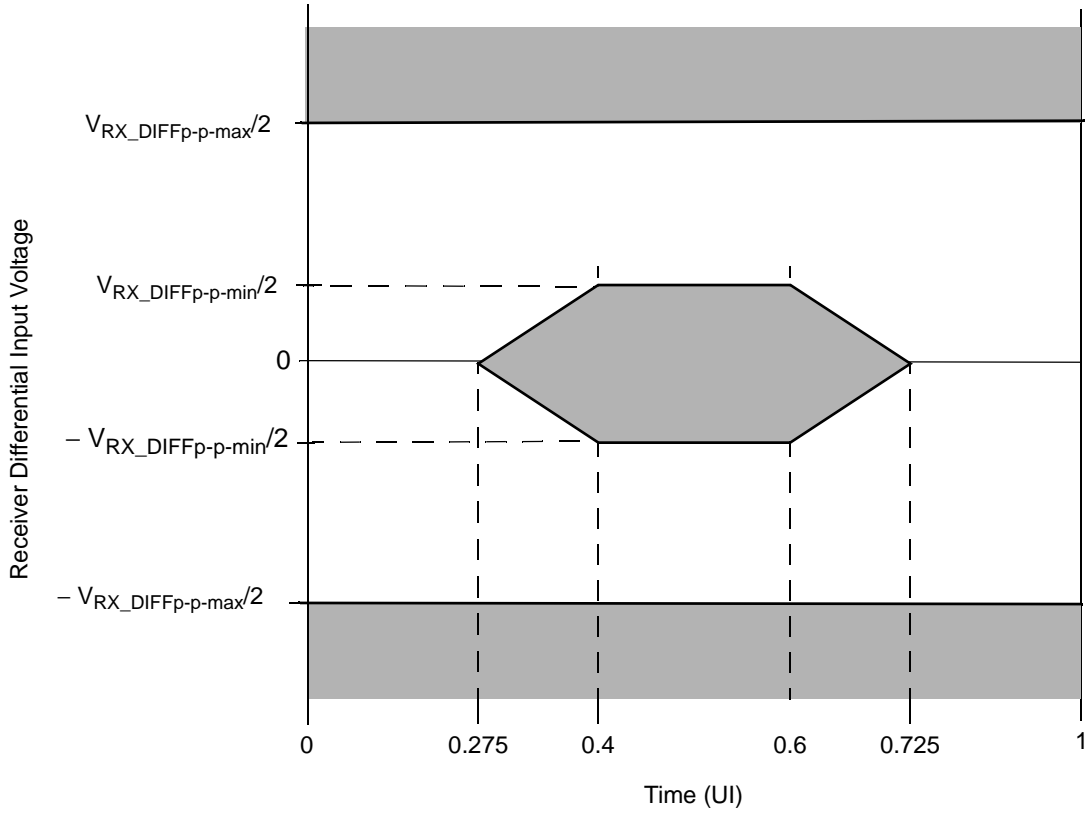


Figure 24. SGMII Receiver Input Compliance Mask

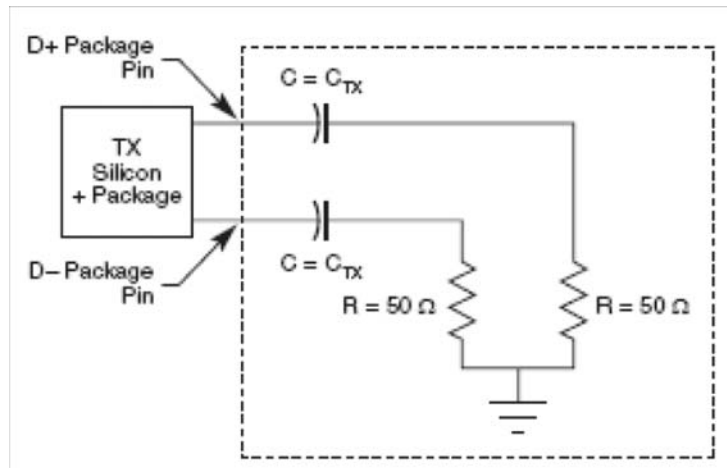


Figure 25. SGMII AC Test/Measurement Load

Table 43. MII Management DC Electrical Characteristics (LV_{DD}/TV_{DD}=3.3 V) (continued)

Parameter	Symbol	Min	Max	Unit	Notes
Input low current (LV _{DD} /TV _{DD} = Max, V _{IN} = 0.5 V)	I _{IL}	-600	—	μA	—

Note:

1. EC1_MDC and EC1_MDIO operate on LV_{DD}.
2. EC3_MDC & EC3_MDIO and EC5_MDC & EC5_MDIO operate on TV_{DD}.
3. Note that the symbol V_{IN}, in this case, represents the LV_{IN} and TV_{IN} symbol referenced in [Table 1](#).

Table 44. MII Management DC Electrical Characteristics (LV_{DD}/TV_{DD}=2.5 V)

Parameters	Symbol	Min	Max	Unit	Notes
Supply voltage 2.5 V	LV _{DD} /TV _{DD}	2.37	2.63	V	1,2
Output high voltage (LV _{DD} /TV _{DD} = Min, I _{OH} = -1.0 mA)	V _{OH}	2.00	LV _{DD} /TV _{DD} + 0.3	V	—
Output low voltage (LV _{DD} /TV _{DD} = Min, I _{OL} = 1.0 mA)	V _{OL}	GND - 0.3	0.40	V	—
Input high voltage	V _{IH}	1.70	LV _{DD} /TV _{DD} + 0.3	V	—
Input low voltage	V _{IL}	-0.3	0.70	V	—
Input high current (V _{IN} = LV _{DD} , V _{IN} = TV _{DD})	I _{IH}	—	10	μA	1, 2,3
Input low current (V _{IN} = GND)	I _{IL}	-15	—	μA	3

Note:

1. EC1_MDC and EC1_MDIO operate on LV_{DD}.
2. EC3_MDC & EC3_MDIO and EC5_MDC & EC5_MDIO operate on TV_{DD}.
3. Note that the symbol V_{IN}, in this case, represents the LV_{IN} and TV_{IN} symbols referenced in [Table 1](#).

9.2 MII Management AC Electrical Specifications

[Table 45](#) provides the MII management AC timing specifications. There are three sets of Ethernet management signals (EC1_MDC and EC1_MDIO, EC3_MDC and EC3_MDIO, EC5_MDC and EC5_MDIO). These are not explicitly shown in the table or in the figure following.

Table 45. MII Management AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 3.3 V ± 5% or 2.5 V ± 5%.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit	Notes
EC _n _MDC frequency	f _{MDC}	0.9	2.5	9.3	MHz	2, 3
EC _n _MDC period	t _{MDC}	107.5	—	1120	ns	—
EC _n _MDC clock pulse width high	t _{MDCH}	32	—	—	ns	—
EC _n _MDC to EC _n _MDIO delay	t _{MDKHDX}	10	—	16*t _{plb_clk}	ns	5

Table 50. Local Bus General Timing Parameters (BV_{DD} = 2.5 V DC)—PLL Enabled (continued)

At recommended operating conditions with BV_{DD} of 2.5 V ± 5% (continued)

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus clock to output valid (except LAD/LDP and LALE)	t _{LBKHOV1}	—	2.4	ns	—
Local bus clock to data valid for LAD/LDP	t _{LBKHOV2}	—	2.5	ns	3
Local bus clock to address valid for LAD	t _{LBKHOV3}	—	2.4	ns	3
Local bus clock to LALE assertion	t _{LBKHOV4}	—	2.4	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	t _{LBKHOX1}	0.8	—	ns	3
Output hold from local bus clock for LAD/LDP	t _{LBKHOX2}	0.8	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	t _{LBKHOZ1}	—	2.6	ns	5
Local bus clock to output high impedance for LAD/LDP	t _{LBKHOZ2}	—	2.6	ns	5

Note:

- The symbols used for timing specifications herein follow the pattern of t_{(First two letters of functional block)(signal)(state)(reference)(state)} for inputs and t_{(First two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{LBIXKH1} symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
- All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
- All signals are measured from BV_{DD}/2 of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to 0.4 × BV_{DD} of the signal in question for 2.5-V signaling levels.
- Input timings are measured at the pin.
- For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
- t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
- Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at BV_{DD}/2.
- Guaranteed by design.

Table 51 describes the general timing parameters of the local bus interface at BV_{DD} = 1.8 V DC

Table 51. Local Bus General Timing Parameters (BV_{DD} = 1.8 V DC)—PLL Enabled

At recommended operating conditions with BV_{DD} of 1.8 V ± 5%

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t _{LBK}	6.67	12	ns	2
Local bus duty cycle	t _{LBKH} /t _{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	t _{LBKSKEW}	—	150	ps	7, 8
Input setup to local bus clock (except LGTĀ/LUPWAIT)	t _{LBIVKH1}	2.4	—	ns	3, 4
LGTĀ/LUPWAIT input setup to local bus clock	t _{LBIVKH2}	1.9	—	ns	3, 4
Input hold from local bus clock (except LGTĀ/LUPWAIT)	t _{LBIXKH1}	1.1	—	ns	3, 4

$\overline{SD1_REF_CLK}$ for PCI Express and Serial RapidIO, or $SD2_REF_CLK$ and $\overline{SD2_REF_CLK}$ for the SGMII interface respectively.

The following sections describe the SerDes reference clock requirements and some application information.

15.2.1 SerDes Reference Clock Receiver Characteristics

Figure 44 shows a receiver reference diagram of the SerDes reference clocks. Characteristics are as follows:

- The supply voltage requirements for XV_{DD_SRDS2} are specified in Table 1 and Table 2.
- SerDes Reference Clock Receiver Reference Circuit Structure
 - The SDn_REF_CLK and $\overline{SDn_REF_CLK}$ are internally AC-coupled differential inputs as shown in Figure 44. Each differential clock input (SDn_REF_CLK or $\overline{SDn_REF_CLK}$) has on-chip $50\text{-}\Omega$ termination to $SGND_SRDSn$ ($xcorevss$) followed by on-chip AC-coupling.
 - The external reference clock driver must be able to drive this termination.
 - The SerDes reference clock input can be either differential or single-ended. Refer to the Differential Mode and Single-ended Mode description below for further detailed requirements.
- The maximum average current requirement that also determines the common mode voltage range
 - When the SerDes reference clock differential inputs are DC coupled externally with the clock driver chip, the maximum average current allowed for each input pin is 8 mA. In this case, the exact common mode input voltage is not critical as long as it is within the range allowed by the maximum average current of 8 mA (refer to the following bullet for more detail), because the input is AC-coupled on-chip.
 - This current limitation sets the maximum common mode input voltage to be less than 0.4 V ($0.4\text{ V}/50 = 8\text{ mA}$) while the minimum common mode input level is 0.1 V above $SGND_SRDSn$ ($xcorevss$). For example, a clock with a 50/50 duty cycle can be produced by a clock driver with output driven by its current source from 0 mA to 16 mA (0-0.8 V), such that each phase of the differential input has a single-ended swing from 0 V to 800 mV with the common mode voltage at 400 mV.
 - If the device driving the SDn_REF_CLK and $\overline{SDn_REF_CLK}$ inputs cannot drive $50\ \Omega$ to $SGND_SRDSn$ ($xcorevss$) DC, or it exceeds the maximum input current limitations, then it must be AC-coupled off-chip.
- The input amplitude requirement
 - This requirement is described in detail in the following sections.

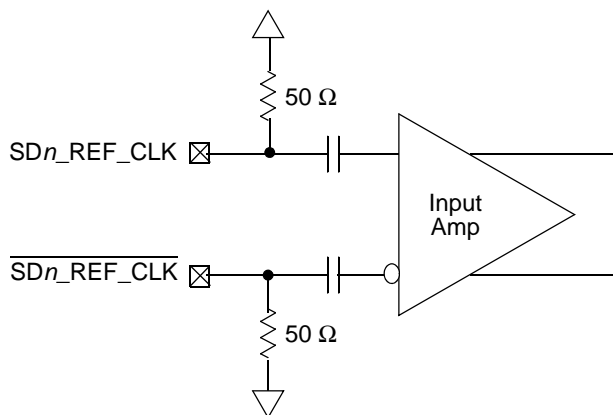


Figure 44. Receiver of SerDes Reference Clocks

15.2.2 DC Level Requirement for SerDes Reference Clocks

The DC level requirement for the MPC8572E SerDes reference clock inputs is different depending on the signaling mode used to connect the clock driver chip and SerDes reference clock inputs as described below.

- **Differential Mode**

- The input amplitude of the differential clock must be between 400mV and 1600mV differential peak-peak (or between 200mV and 800mV differential peak). In other words, each signal wire of the differential pair must have a single-ended swing less than 800mV and greater than 200mV. This requirement is the same for both external DC-coupled or AC-coupled connection.
- For **external DC-coupled** connection, as described in [Section 15.2.1, “SerDes Reference Clock Receiver Characteristics,”](#) the maximum average current requirements sets the requirement for average voltage (common mode voltage) to be between 100 mV and 400 mV. [Figure 45](#) shows the SerDes reference clock input requirement for DC-coupled connection scheme.
- For **external AC-coupled** connection, there is no common mode voltage requirement for the clock driver. Because the external AC-coupling capacitor blocks the DC level, the clock driver and the SerDes reference clock receiver operate in different command mode voltages. The SerDes reference clock receiver in this connection scheme has its common mode voltage set to SGND_SRDS_n. Each signal wire of the differential inputs is allowed to swing below and above the command mode voltage (SGND_SRDS_n). [Figure 46](#) shows the SerDes reference clock input requirement for AC-coupled connection scheme.

- **Single-ended Mode**

- The reference clock can also be single-ended. The SD_n_REF_CLK input amplitude (single-ended swing) must be between 400 mV and 800 mV peak-peak (from V_{min} to V_{max}) with $\overline{\text{SD}}_n\text{_REF_CLK}$ either left unconnected or tied to ground.
- The SD_n_REF_CLK input average voltage must be between 200 and 400 mV. [Figure 47](#) shows the SerDes reference clock input requirement for single-ended signaling mode.

Figure 48 shows the SerDes reference clock connection reference circuits for HCSL type clock driver. It assumes that the DC levels of the clock driver chip is compatible with MPC8572E SerDes reference clock input's DC requirement.

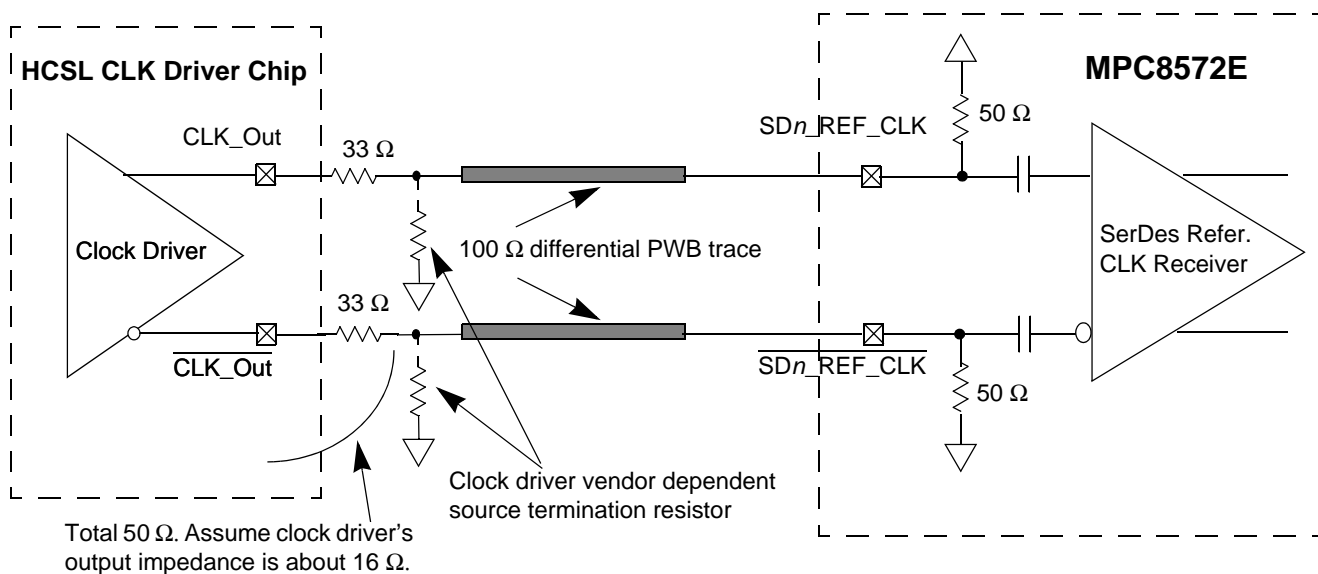


Figure 48. DC-Coupled Differential Connection with HCSL Clock Driver (Reference Only)

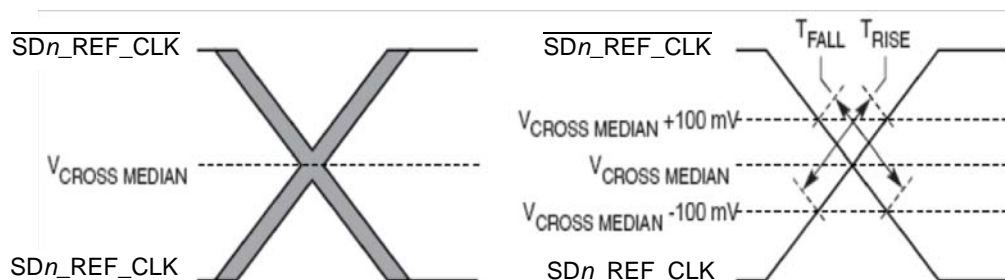


Figure 53. Single-Ended Measurement Points for Rise and Fall Time Matching

The other detailed AC requirements of the SerDes Reference Clocks is defined by each interface protocol based on application usage. Refer to the following sections for detailed information:

- [Section 8.3.2, “AC Requirements for SGMII SD2_REF_CLK and SD2_REF_CLK”](#)
- [Section 16.2, “AC Requirements for PCI Express SerDes Reference Clocks”](#)
- [Section 17.2, “AC Requirements for Serial RapidIO SD1_REF_CLK and SD1_REF_CLK”](#)

15.2.4.1 Spread Spectrum Clock

SD1_REF_CLK/SD1_REF_CLK are designed to work with a spread spectrum clock (+0 to -0.5% spreading at 30–33 KHz rate is allowed), assuming both ends have same reference clock. For better results, a source without significant unintended modulation should be used.

SD2_REF_CLK/SD2_REF_CLK are not to be used with, and should not be clocked by, a spread spectrum clock source.

15.3 SerDes Transmitter and Receiver Reference Circuits

Figure 54 shows the reference circuits for SerDes data lane’s transmitter and receiver.

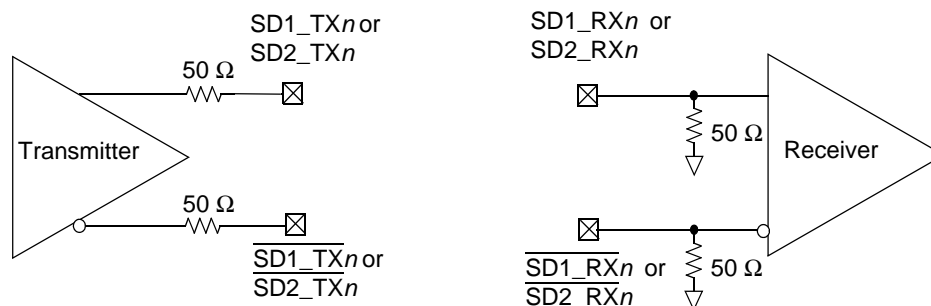


Figure 54. SerDes Transmitter and Receiver Reference Circuits

The DC and AC specification of SerDes data lanes are defined in each interface protocol section below (PCI Express, Serial Rapid IO or SGMII) in this document based on the application usage:

- [Section 8.3, “SGMII Interface Electrical Characteristics”](#)
- [Section 16, “PCI Express”](#)

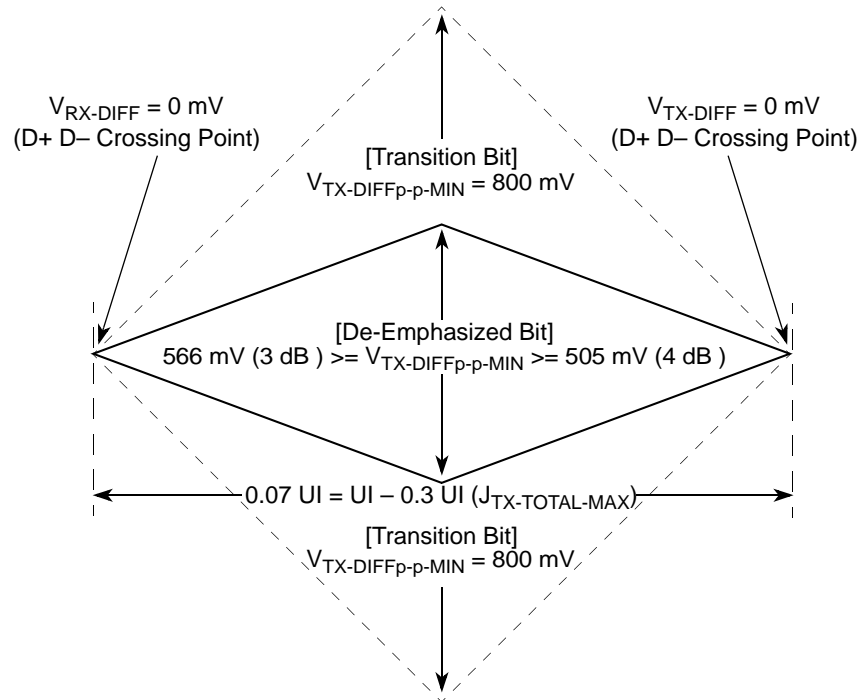


Figure 55. Minimum Transmitter Timing and Voltage Output Compliance Specifications

16.4.3 Differential Receiver (RX) Input Specifications

Table 63 defines the specifications for the differential input at all receivers (RXs). The parameters are specified at the component pins.

Table 63. Differential Receiver (RX) Input Specifications

Symbol	Parameter	Min	Nominal	Max	Units	Comments
UI	Unit Interval	399.88	400	400.12	ps	Each UI is 400 ps \pm 300 ppm. UI does not account for Spread Spectrum Clock dictated variations. See Note 1.
$V_{RX-DIFFp-p}$	Differential Input Peak-to-Peak Voltage	0.175	—	1.200	V	$V_{RX-DIFFp-p} = 2 * V_{RX-D+} - V_{RX-D-} $ See Note 2.
T_{RX-EYE}	Minimum Receiver Eye Width	0.4	—	—	UI	The maximum interconnect media and Transmitter jitter that can be tolerated by the Receiver can be derived as $T_{RX-MAX-JITTER} = 1 - T_{RX-EYE} = 0.6$ UI. See Notes 2 and 3.

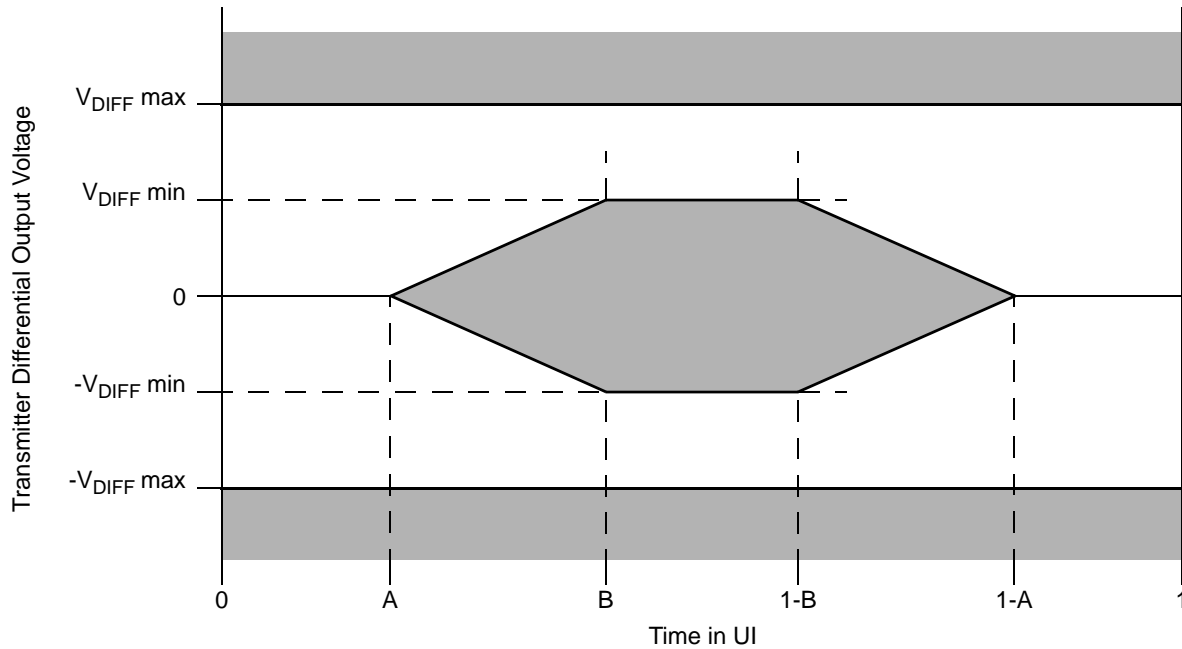


Figure 58. Transmitter Output Compliance Mask

Table 71. Transmitter Differential Output Eye Diagram Parameters

Transmitter Type	$V_{DIFFmin}$ (mV)	$V_{DIFFmax}$ (mV)	A (UI)	B (UI)
1.25 GBaud short range	250	500	0.175	0.39
1.25 GBaud long range	400	800	0.175	0.39
2.5 GBaud short range	250	500	0.175	0.39
2.5 GBaud long range	400	800	0.175	0.39
3.125 GBaud short range	250	500	0.175	0.39
3.125 GBaud long range	400	800	0.175	0.39

17.6 Receiver Specifications

LP-Serial receiver electrical and timing specifications are stated in the text and tables of this section.

Receiver input impedance shall result in a differential return loss better than 10 dB and a common mode return loss better than 6 dB from 100 MHz to $(0.8) \times$ (Baud Frequency). This includes contributions from on-chip circuitry, the chip package and any off-chip components related to the receiver. AC coupling components are included in this requirement. The reference impedance for return loss measurements is 100 Ohm resistive for differential return loss and 25- Ω resistive for common mode.

Table 72. Receiver AC Timing Specifications—1.25 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V_{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance ¹	J_T	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10^{-12}	—	—
Unit Interval	UI	800	800	ps	+/- 100 ppm

Note:

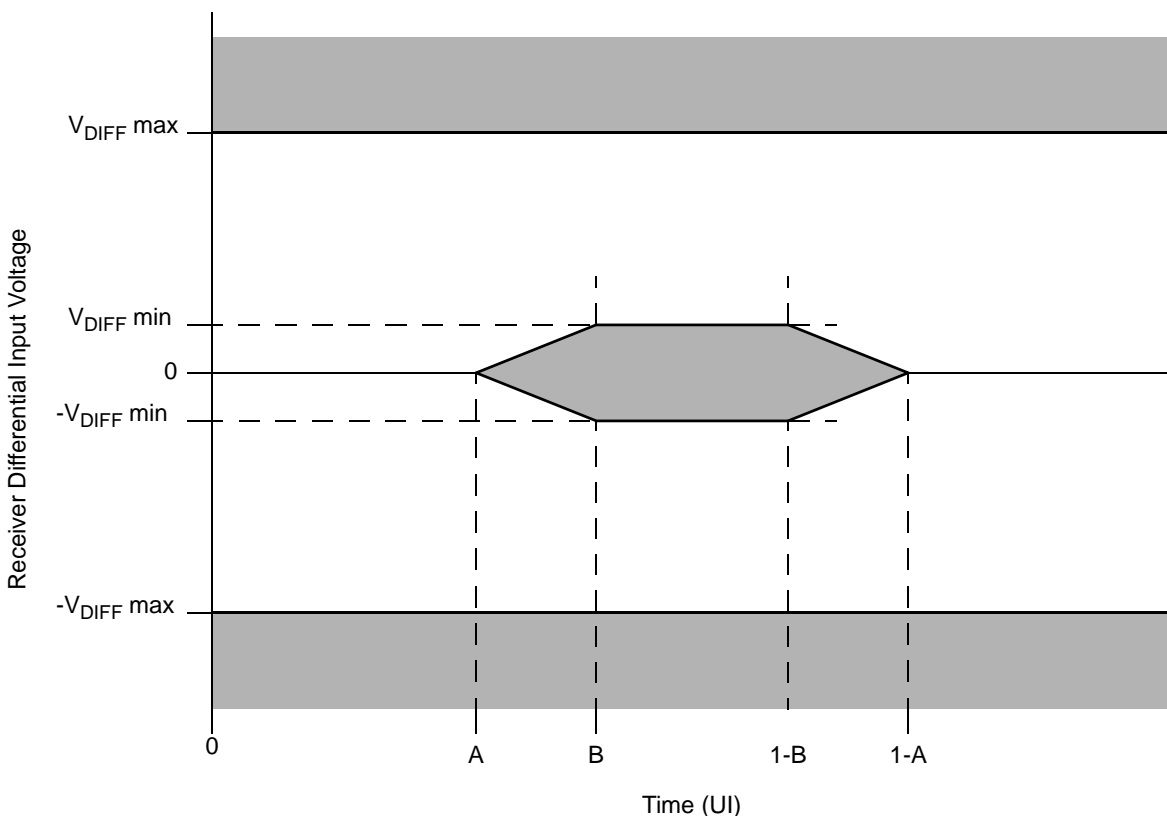
- Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of [Figure 59](#). The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

Table 73. Receiver AC Timing Specifications—2.5 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V_{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance ¹	J_T	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S_{MI}	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10^{-12}	—	—
Unit Interval	UI	400	400	ps	+/- 100 ppm

Note:

- Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of [Figure 59](#). The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.


Figure 60. Receiver Input Compliance Mask
Table 75. Receiver Input Compliance Mask Parameters Exclusive of Sinusoidal Jitter

Receiver Type	$V_{DIFFmin}$ (mV)	$V_{DIFFmax}$ (mV)	A (UI)	B (UI)
1.25 GBaud	100	800	0.275	0.400
2.5 GBaud	100	800	0.275	0.400
3.125 GBaud	100	800	0.275	0.400

17.8 Measurement and Test Requirements

Because the LP-Serial electrical specifications are guided by the XAUI electrical interface specified in Clause 47 of IEEE 802.3ae-2002, the measurement and test requirements defined here are similarly guided by Clause 47. Additionally, the CJPAT test pattern defined in Annex 48A of IEEE 802.3ae-2002 is specified as the test pattern for use in eye pattern and jitter measurements. Annex 48B of IEEE 802.3ae-2002 is recommended as a reference for additional information on jitter test methods.

17.8.1 Eye Template Measurements

For the purpose of eye template measurements, the effects of a single-pole high pass filter with a 3 dB point at $(\text{Baud Frequency})/1667$ is applied to the jitter. The data pattern for template measurements is the Continuous Jitter Test Pattern (CJPAT) defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-Serial

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
D2_MBA[0:2]	Bank Select	Y1, W3, P3	O	GV _{DD}	—
$\overline{\text{D2_MWE}}$	Write Enable	AA2	O	GV _{DD}	—
$\overline{\text{D2_MCAS}}$	Column Address Strobe	AD1	O	GV _{DD}	—
$\overline{\text{D2_MRAS}}$	Row Address Strobe	AA1	O	GV _{DD}	—
D2_MCKE[0:3]	Clock Enable	L3, L1, K1, K2	O	GV _{DD}	11
$\overline{\text{D2_MCS}}[0:3]$	Chip Select	AB1, AG2, AC1, AH2	O	GV _{DD}	—
D2_MCK[0:5]	Clock	V4, F7, AJ3, V2, E7, AG4	O	GV _{DD}	—
$\overline{\text{D2_MCK}}[0:5]$	Clock Complements	V1, F8, AJ4, U1, E6, AG5	O	GV _{DD}	—
D2_MODT[0:3]	On Die Termination	AE1, AG1, AE2, AH1	O	GV _{DD}	—
D2_MDIC[0:1]	Driver Impedance Calibration	F1, G1	I/O	GV _{DD}	25
Local Bus Controller Interface					
LAD[0:31]	Muxed Data/Address	M22, L22, F22, G22, F21, G21, E20, H22, K22, K21, H19, J20, J19, L20, M20, M19, E22, E21, L19, K19, G19, H18, E18, G18, J17, K17, K14, J15, H16, J14, H15, G15	I/O	BV _{DD}	34
LDP[0:3]	Data Parity	M21, D22, A24, E17	I/O	BV _{DD}	—
LA[27]	Burst Address	J21	O	BV _{DD}	5, 9
LA[28:31]	Port Address	F20, K18, H20, G17	O	BV _{DD}	5, 7, 9
$\overline{\text{LCS}}[0:4]$	Chip Selects	B23, E16, D20, B25, A22	O	BV _{DD}	10
$\overline{\text{LCS}}[5]/\overline{\text{DMA2_DREQ}}[1]$	Chip Selects / DMA Request	D19	I/O	BV _{DD}	1, 10
$\overline{\text{LCS}}[6]/\overline{\text{DMA2_DACK}}[1]$	Chip Selects / DMA Ack	E19	O	BV _{DD}	1, 10
$\overline{\text{LCS}}[7]/\overline{\text{DMA2_DDONE}}[1]$	Chip Selects / DMA Done	C21	O	BV _{DD}	1, 10
$\overline{\text{LWE}}[0]/\overline{\text{LBS}}[0]/\overline{\text{LFWE}}$	Write Enable / Byte Select	D17	O	BV _{DD}	5, 9
$\overline{\text{LWE}}[1]/\overline{\text{LBS}}[1]$	Write Enable / Byte Select	F15	O	BV _{DD}	5, 9
$\overline{\text{LWE}}[2]/\overline{\text{LBS}}[2]$	Write Enable / Byte Select	B24	O	BV _{DD}	5, 9
$\overline{\text{LWE}}[3]/\overline{\text{LBS}}[3]$	Write Enable / Byte Select	D18	O	BV _{DD}	5, 9
LALE	Address Latch Enable	F19	O	BV _{DD}	5, 8, 9
LBCTL	Buffer Control	L18	O	BV _{DD}	5, 8, 9

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
SGND_SRDS1	SerDes Transceiver Core Logic GND (xcorevss)	C28, C32, D30, E31, F28, F29, G32, H28, H30, J28, K29, L32, M30, N31, P29, R32	—	—	—
SGND_SRDS2	SerDes Transceiver Core Logic GND (xcorevss)	AE28, AE30, AF28, AF32, AG28, AG30, AH28, AJ28, AJ31, AL32	—	—	—
AGND_SRDS1	SerDes PLL GND	J31	—	—	—
AGND_SRDS2	SerDes PLL GND	AH31	—	—	—
OVDD	General I/O Supply	U31, V24, V28, Y31, AA27, AB25, AB29	—	OVDD	—
LVDD	TSEC 1&2 I/O Supply	AC18, AC21, AG21, AL27	—	LVDD	—
TVDD	TSEC 3&4 I/O Supply	AC15, AE16, AH18	—	TVDD	—
GVDD	SSTL_1.8 DDR Supply	B2, B5, B8, B11, B14, D4, D7, D10, D13, E2, F6, F9, F12, G4, H2, H8, H11, H14, J6, K4, K10, K13, L2, L8, M6, N4, N10, P2, P8, R6, T4, T10, U2, U8, V6, W4, W10, Y2, Y8, AA6, AB4, AB10, AC2, AC8, AD6, AD12, AE4, AE10, AF2, AF8, AG6, AG12, AH4, AH10, AH16, AJ2, AJ8, AJ14, AK6, AK12, AK18, AL4, AL10, AL16, AM2	—	GVDD	—
BVDD	Local Bus and GPIO Supply	A26, A30, B21, D16, D21, F18, G20, H17, J22, K15, K20	—	BVDD	—

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
SD1_IMP_CAL_RX	SerDes1 Rx Impedance Calibration	B32	I	200Ω (±1%) to GND	—
SD1_IMP_CAL_TX	SerDes1 Tx Impedance Calibration	T32	I	100Ω (±1%) to GND	—
SD1_PLL_TPA	SerDes1 PLL Test Point Analog	J30	O	AVDD_S RDS analog	17
SD2_IMP_CAL_RX	SerDes2 Rx Impedance Calibration	AC32	I	200Ω (±1%) to GND	—
SD2_IMP_CAL_TX	SerDes2 Tx Impedance Calibration	AM32	I	100Ω (±1%) to GND	—
SD2_PLL_TPA	SerDes2 PLL Test Point Analog	AH30	O	AVDD_S RDS analog	17
TEMP_ANODE	Temperature Diode Anode	AA31	—	internal diode	14
TEMP_CATHODE	Temperature Diode Cathode	AB31	—	internal diode	14
No Connection Pins					

Table 85 summarizes the signal impedance targets. The driver impedances are targeted at minimum V_{DD} , nominal OV_{DD} , 105°C.

Table 85. Impedance Characteristics

Impedance	Local Bus, Ethernet, DUART, Control, Configuration, Power Management	DDR DRAM	Symbol	Unit
R_N	45 Target	18 Target (full strength mode) 36 Target (half strength mode)	Z_0	Ω
R_P	45 Target	18 Target (full strength mode) 36 Target (half strength mode)	Z_0	Ω

Note: Nominal supply voltages. See Table 1, $T_j = 105^\circ\text{C}$.

21.8 Configuration Pin Muxing

The MPC8572E provides the user with power-on configuration options which can be set through the use of external pull-up or pull-down resistors of 4.7 k Ω on certain output pins (see customer visible configuration pins). These pins are generally used as output only pins in normal operation.

While $\overline{\text{HRESET}}$ is asserted however, these pins are treated as inputs. The value presented on these pins while $\overline{\text{HRESET}}$ is asserted, is latched when $\overline{\text{HRESET}}$ deasserts, at which time the input receiver is disabled and the I/O circuit takes on its normal function. Most of these sampled configuration pins are equipped with an on-chip gated resistor of approximately 20 k Ω . This value should permit the 4.7-k Ω resistor to pull the configuration pin to a valid logic low level. The pull-up resistor is enabled only during $\overline{\text{HRESET}}$ (and for platform /system clocks after $\overline{\text{HRESET}}$ deassertion to ensure capture of the reset value). When the input receiver is disabled the pull-up is also, thus allowing functional operation of the pin as an output with minimal signal quality or delay disruption. The default value for all configuration bits treated this way has been encoded such that a high voltage level puts the device into the default state and external resistors are needed only when non-default settings are required by the user.

Careful board layout with stubless connections to these pull-down resistors coupled with the large value of the pull-down resistor should minimize the disruption of signal quality or speed for output pins thus configured.

The platform PLL ratio, DDR complex PLL and e500 PLL ratio configuration pins are not equipped with these default pull-up devices.

21.9 JTAG Configuration Signals

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in Figure 66. Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion gives unpredictable results.

Boundary-scan testing is enabled through the JTAG interface signals. The $\overline{\text{TRST}}$ signal is optional in the IEEE Std 1149.1 specification, but it is provided on all processors built on Power Architecture technology. The device requires $\overline{\text{TRST}}$ to be asserted during power-on reset flow to ensure that the JTAG boundary

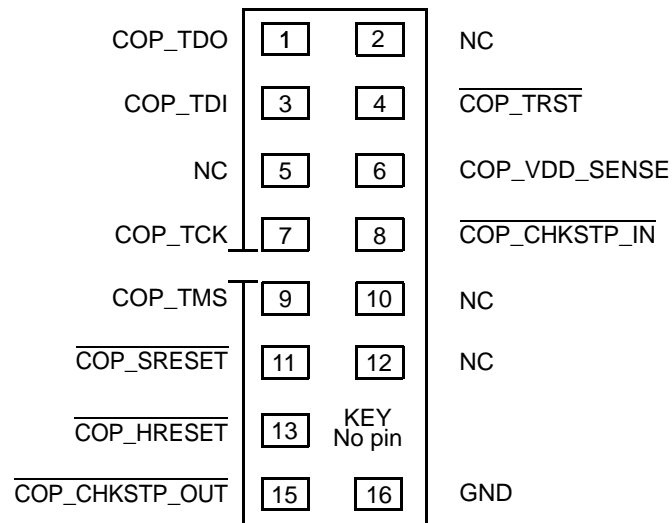


Figure 65. COP Connector Physical Pinout